<u>Update on</u> <u>CERN/GE Source Measurements</u>



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The CERN/GE Source Setup





~6% above MIP

- •Use TRIN feature of CLOAC
- Use BurstType "20" (External Trigger)
 - (External Trigger)
- •Use Trigger Window Feature of CLOAC

The Timing

- →Choose Time Window 5 ns
- →Optimize Window/Trigger Delay by counting hits above ~2 fC
- →Use LevelMode X1X for correct determination of noise

BunchCrossing	WindowDelay	
123	7	
124	12	
124	12	
124	12	
123	5	
123	7	
	BunchCrossing 123 124 124 124 123 123	

B044* courtesy by Janet Carter, Nobu Unno et al.





'Beam Profile'



- 0.5 ... 5.5 fC with 0.1 fC spacing20000 triggers per point1.... 11 channels summed in region of interest

The Method: Derivative of Threshold Scan



Goal: Recover the analog information from threshold scan -> S/N

not as straightforward as it sounds (systematics of numerical finite derivative etc ...) numbers here on S/N, and absolute N and S still preliminary but usable for "figure- of- merit" comparison of modules second angle on standard perf. determinations (TB, electrical tests)

Source Pulse Height Expectation



CLEOSilicon,

K5-303 (unirradiated)



HV=150 VSum 3 channels region

- Recover Gaussian Noise
 Recover Landau (plus Charge Sharing Shoulder...)
- * but Noise Gaussians are not centered at 0 ... ???
- -> subtract offsets

 $S^{mp}/N \sim 13$

K5-310* and K5-312*



 $S^{mp}/N \sim 10$ $S^{mp}/N \sim 10$ NB: modules have only seen 50% of nominal 10 yr LHC flux

* Noise Gaussians postions are fluctuating channel by channel 0.0...0.4 fC

K5-308* and Barrel B044*

Х



 $S^{mp}/N \sim 8$ $S^{mp}/N \sim 9.5$

Barrel has slightly higher noise (0.21 fC vs 0.23 fC) but significantly higher signal (2.18 fC vs 1.70 fC)

Overview:

Module	Corrected Noise (fC)	Input Noise (ENC)	RC Noise (ENC)	Signal (fC)	S/N
303	0.19	1200	1300	2.6	13
310	0.20	1259	1800	2.0	10
312	0.21	1301	1830	2.0	10
308	0.23	1437	2140	1.9	8
B044	0.25	1554	2000	2.4	10

Handle numbers with care: Both S and N need further systematic study

- Unknown charge sharing in the source data
 - -> use smaller channel region to reduce it <-> statistics
 - -> use ntuple analysis a la test beam
- •Threshold variation is taken out of noise determination via offset subtraction => worse for irradiated modules where do these offsets come from ?
- Noise determination assumes linearity of electronics down to 0 fC what happens below 0.5 fC ??

Nonlinearity?



For K5-303, threshold offsets correspond to noise gaussian offsets

Nonlinearity?

Module k5_303 Noise Occupancy



Nonlinearity?



Re-scale 0....0.5 fC area with gain ratio -> increase noise

Further Work

. . . .

- Charge Sharing -> What is the real Signal ?
- Non-Linearity ? Offsets ? -> What is the real Noise ?
- Energy Spectrum -> MonteCarlo Model
- Systematics from Derivative

→ Alternative but non-trivial method for S/N estimation